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# ***Mixed-Level Circuit and Device Simulation***

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# Outline

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- **Introduction**
- **Mixed-level (coupled) circuit/device simulation**
- **Advantages and applications**
- **Simulator architecture and algorithms**
- **Radio frequency (RF) simulation issues**
- **Extensions to microsystem simulation**

# The Modeling Hierarchy

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Speed



Accuracy

High-level  
models

Lumped-  
element  
models

Compact  
models

Numerical  
models

**VHDL-AMS**

**RLC**

**BSIM3**

**PISCES**

# Circuit/Device Simulation

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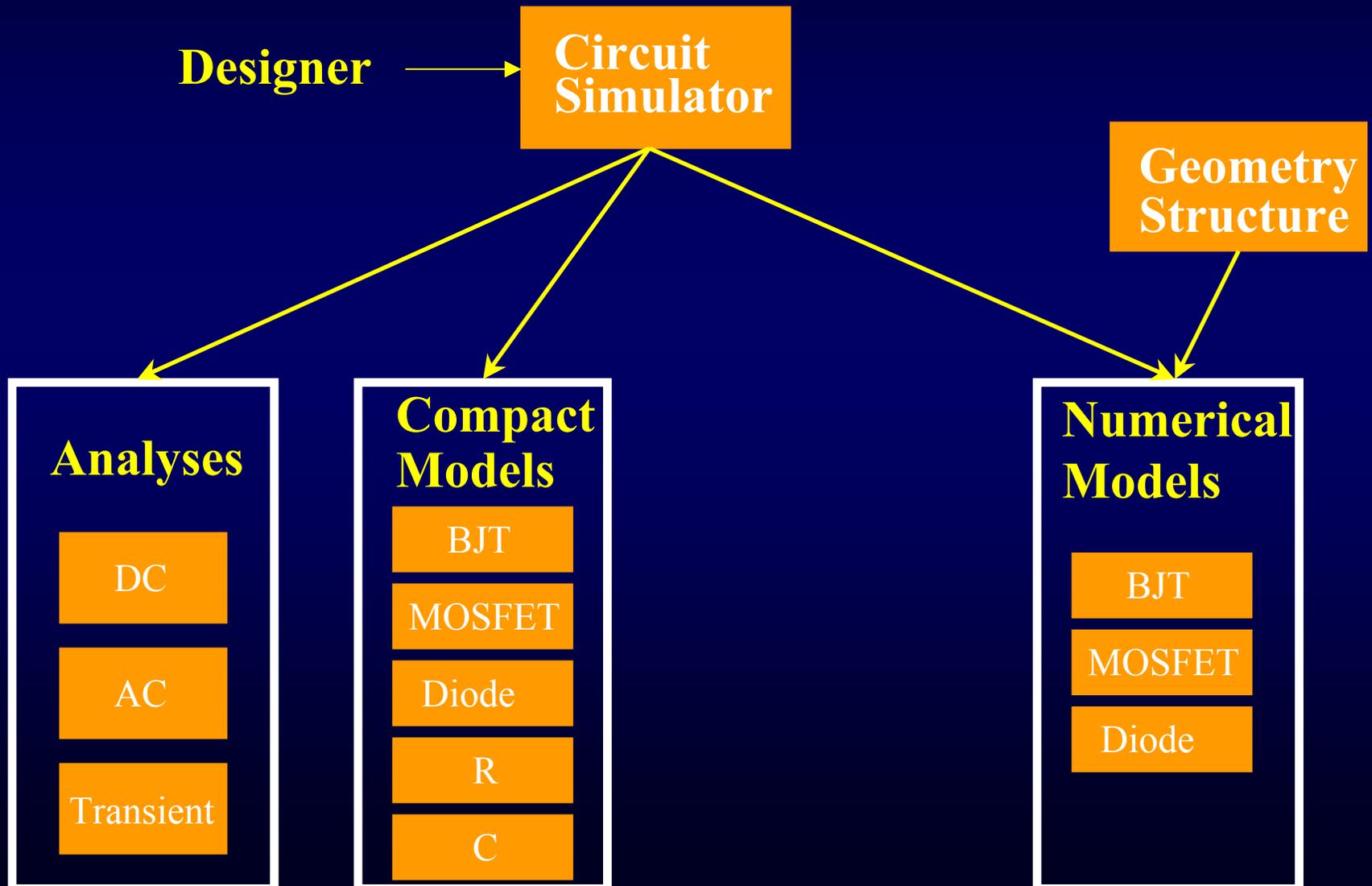
- **Circuit simulation**
  - Analytical (compact) models used: inaccurate under certain conditions
  - + Simulation of multiple devices in a circuit
- **Device simulation**
  - + Based on device physics: accurate
  - Simulation of a single device, no circuit embedding
- **Coupled circuit/device simulation**
  - + Accurate
  - + Simulation of complete systems

# Coupled Circuit/Device Simulator

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- **Compact models for electronic components (BJTs, MOSFETs, ...)**
- **Accurate numerical models for various components**
- **Analysis capabilities supported by the circuit simulator**

# Coupled Circuit/Device Simulator



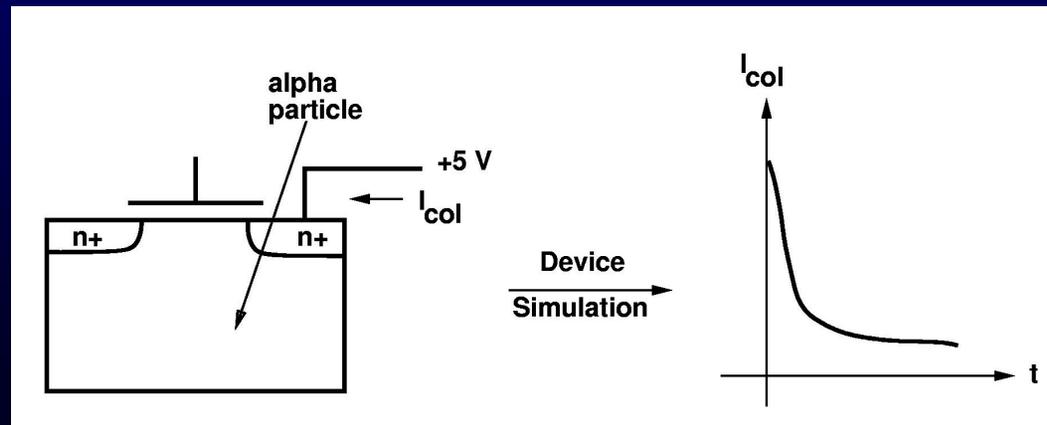
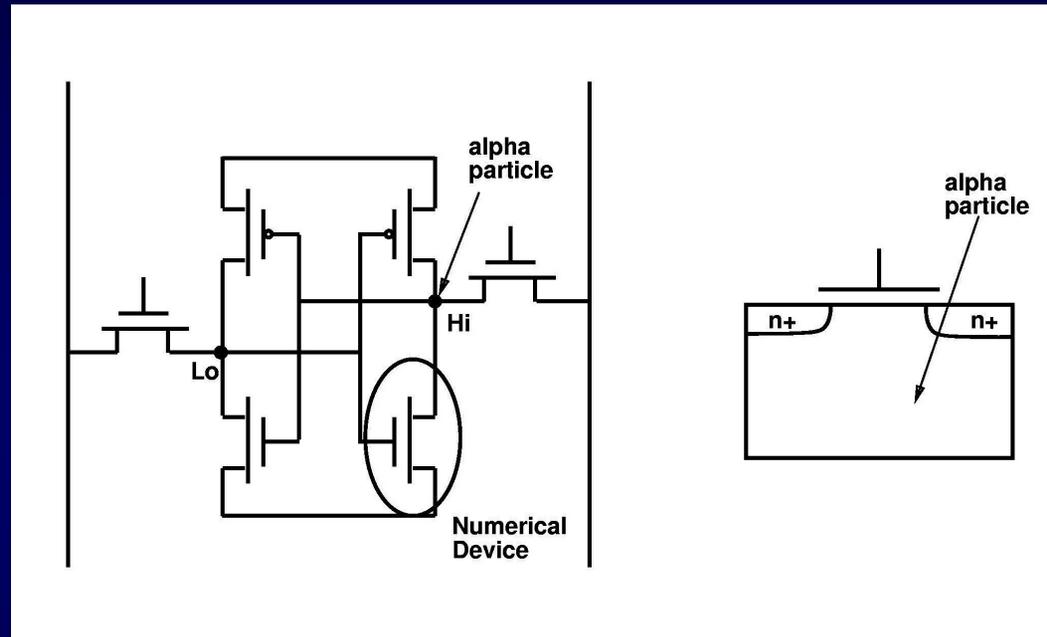
# Advantages

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- **Simulate critical devices at the device level within a circuit**
  - Solve partial differential equations describing devices coupled to a circuit simulator
- **Predict performance of circuits in absence of compact models for devices**
- **Evaluate influence of process variations on circuit performance**

# Application Example – Single Event Upset in SRAM Cell

- Critical transistor modeled at the physical (numerical) level
- Other transistors modeled with compact models
- Alpha particle strike simulated with circuit boundary conditions



# Application Examples

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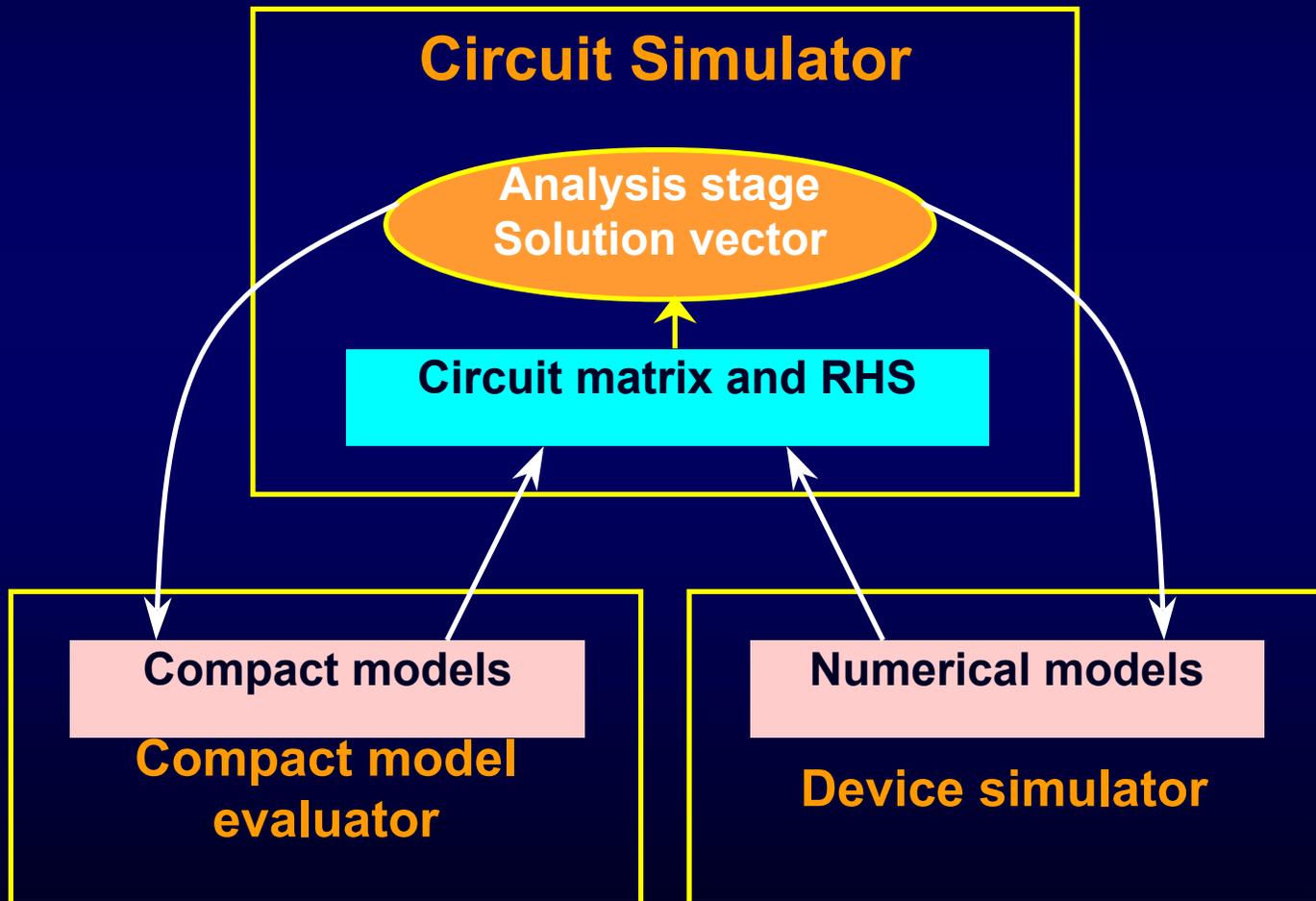
- **Delay analysis of BiCMOS driver circuits**
- **Simulation of power devices**
- **Determination of switch-induced error in MOS switched-capacitor circuits**
- **Simulation of RF circuits**
- **Simulation of single-event-upset in SRAMs**
- **Validation of analytical models**

# Coupled Device and Circuit Simulator (CODECS)

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- **Device-level simulator (PDE solver)**
  - Poisson's and current-continuity equations
  - Accurate terminal conductances and capacitances provided to circuit-level simulator
- **Circuit-level simulator (SPICE3)**
  - Compact model evaluation
  - Simulation engine

# Architecture of CODECS



# Equation Formulation

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- **Modified nodal admittance matrix formulation for circuit equations**

$$\mathbf{F}(\mathbf{x}, \dot{\mathbf{x}}, t) = 0$$

$\mathbf{x}$  is the vector of unknown node voltages and voltage source currents

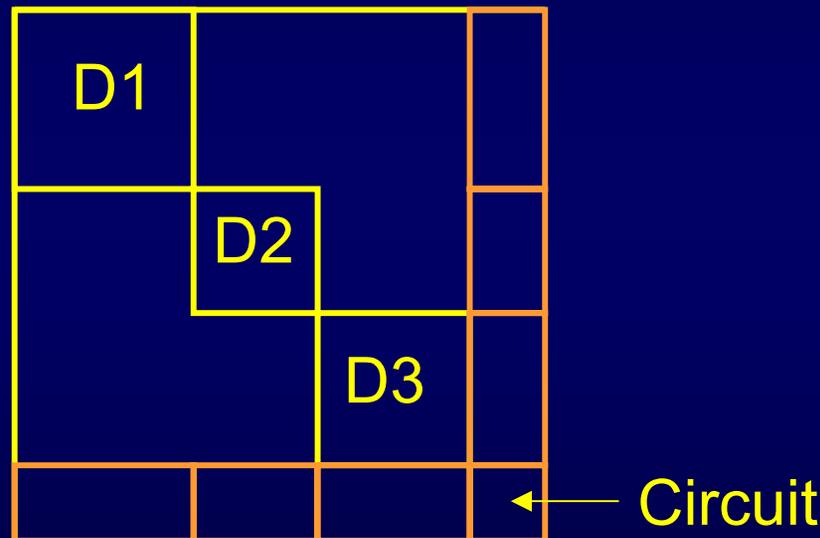
- **Device equations after space discretization can also be expressed as**

$$\mathbf{G}(\mathbf{u}, \dot{\mathbf{u}}, t) = 0$$

$\mathbf{u}$  is the vector of unknown electrostatic potential, electron and hole concentration at each grid point

# Equation Solution

- With voltage boundary conditions for numerical devices and Newton's method



- Full Newton: block LU decomposition used
- Two-level Newton: solve devices to convergence

# Various Equation Solution Methods

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- **Two-level Newton**
- **Modified two-level Newton**
  - Two-level Newton with improved initial guess
- **Full Newton**
- **Block iterative algorithm**
- **Two-level Newton has better convergence but higher computational cost**
  - Use two-level Newton scheme for DC analysis
  - Use full Newton scheme for transient analysis

# DC Analysis Iterations

Circuit	m2lev	2lev	full Newton	blockl t
RTLinv	8	8	8	-
Osc	8	8	9	-
VCO	8	-	10	-
Invchain	9	-	-	-
Astable	9	-	-	-
MECL	51	51	-	-

- No convergence in 100 iterations

# Transient Analysis Iterations

Circuit	m2lev	2lev	full Newton	blockl t
Osc	16916	1691	18333	23836
VCO	5093	5109 <sup>6</sup>	5864	7028
Invchain	1563	1578	1716	2324
Astable	5930	6305	6369	9087
MECL	2450	2450	2609	3236
Cpump	1644	1661	1850	2661

# RF Simulation Issues

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- **Accurate and efficient steady-state simulation of RF ICs required for**
  - Distortion, power, frequency, and noise
  - Gain and impedance characteristics
- **Simulation techniques**
  - Time-domain shooting method
  - Harmonic-balance method

# RF Simulation Issues

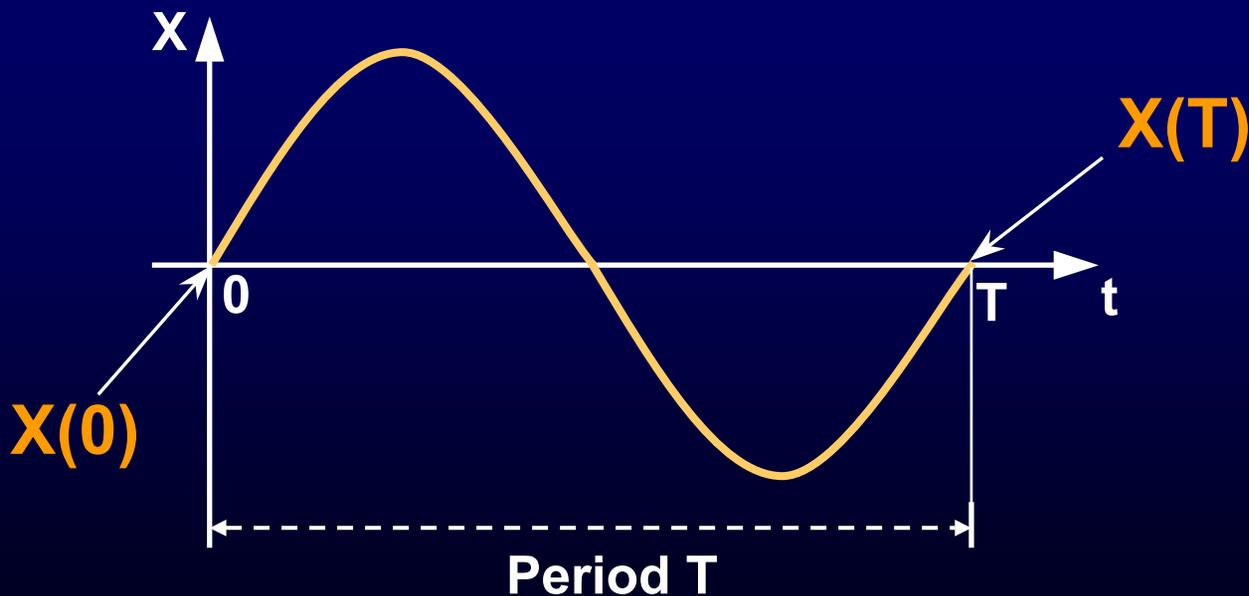
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- **Distributed effects in devices important for RF applications**
  - Use physical models in absence of accurate compact models
    - ⇒ Coupled device and circuit simulation

# Time-Domain Periodic Steady-State Analysis

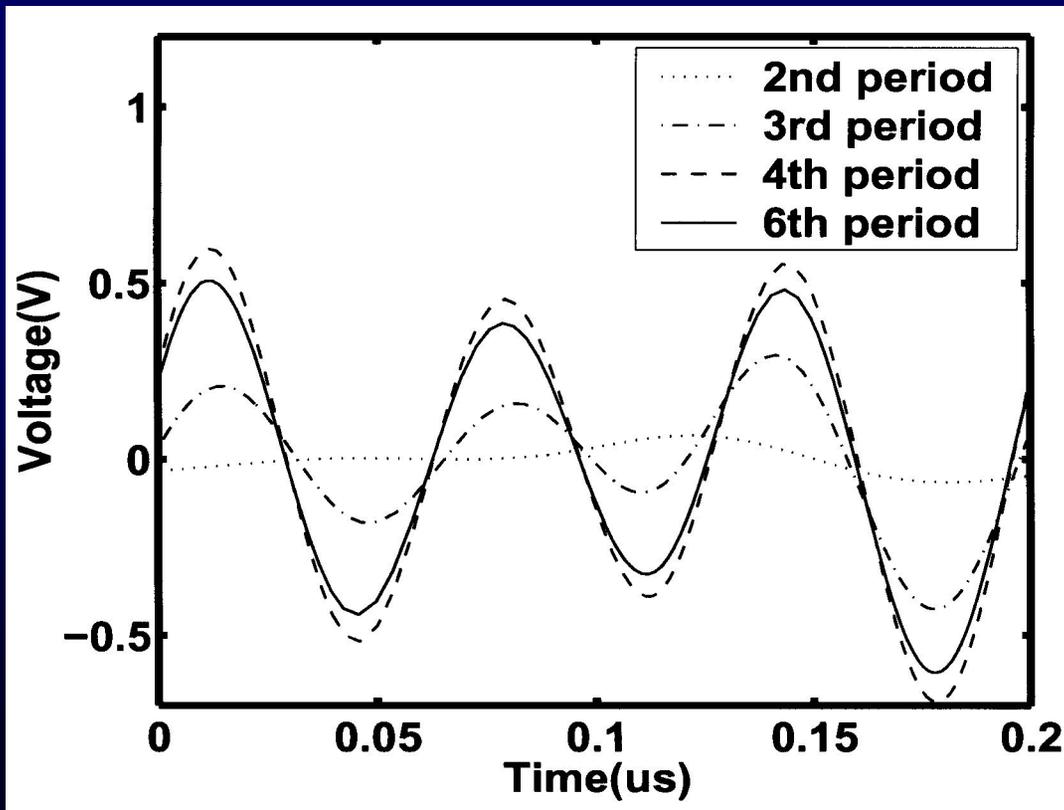
- Two-point boundary value problem

$$X(0) - X(T, X(0)) = 0$$



# Frequency Multiplier Example

- Shooting method: 6 periods
- Conventional transient: 1500 periods



# Harmonic Balance Method

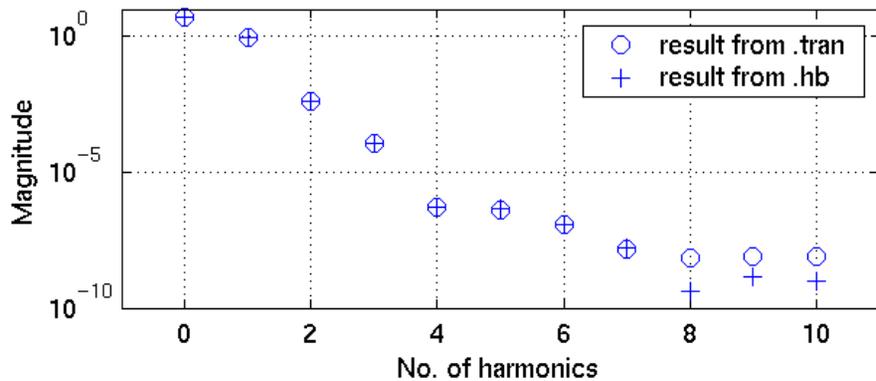
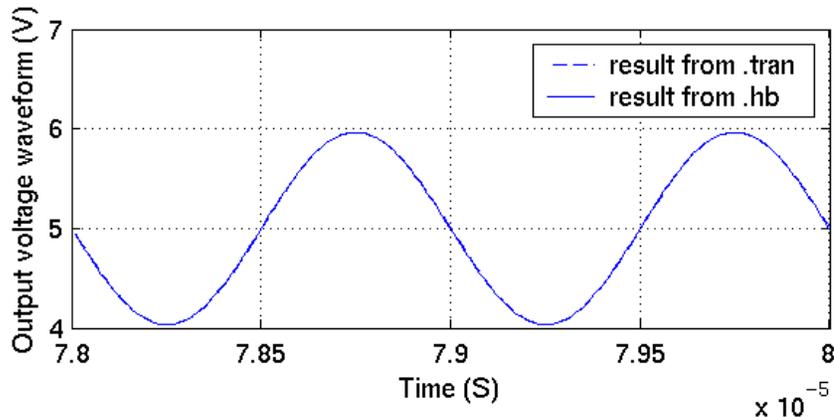
- Truncated Fourier series approximation of  $x(t)$

$$x(t) \approx a_0 + \sum_{i=1}^s (a_i \cos(\omega_i t) + b_i \sin(\omega_i t))$$

- For  $2s+1$  time samples  $x_0 \dots x_{2s}$

$$\mathbf{x} = \begin{bmatrix} x_0 \\ x_1 \\ \vdots \\ x_{2s} \end{bmatrix} = \underbrace{\begin{bmatrix} 1 & \cos(\omega_1 t_0) & \cdots & \sin(\omega_s t_0) \\ 1 & \cos(\omega_1 t_1) & \cdots & \sin(\omega_s t_1) \\ \vdots & \vdots & \ddots & \vdots \\ 1 & \cos(\omega_1 t_{2s}) & \cdots & \sin(\omega_s t_{2s}) \end{bmatrix}}_{\Gamma^{-1}} \underbrace{\begin{bmatrix} a_0 \\ a_1 \\ \vdots \\ b_s \end{bmatrix}}_{\mathbf{X}} = \Gamma^{-1} \mathbf{X}$$

# MOSFET Tuned Amplifier



- 2D numerical MOSFET with 31x19 mesh points
- 10 harmonics
- # iterations = 6
- Result verified by transient simulation

# Periodic Steady-State Analysis: Performance Results

Circuit	Shooting Method		Harmonic balance	
	# Iter	Time (sec)	# Iter	Time (sec)
Simple rectifier	2	28	16	37
DC power supply	6	81	39	45
CB amplifier	4	254	53	385
X3 freq. multiplier	6	10	8	32
MOS CS amplifier	3	554	6	36

# Simulation of Microsystems

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- **Microdevice simulation**
  - Finite-element methods (FEM)
  - Fast integral methods
- **Simulation of complete systems**
  - Lumped equivalent circuit representations
  - Macromodels derived from FEM analysis
  - Analog hardware description language (AHDL) descriptions

# Limitations of High-Level Models

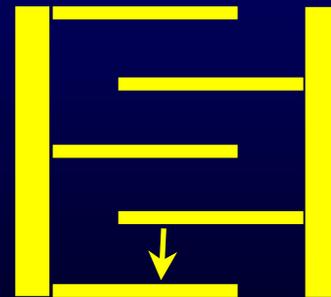
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- Typically derived for small-signal conditions
- Not suitable for systems with feedback
- Cannot predict behavior outside range



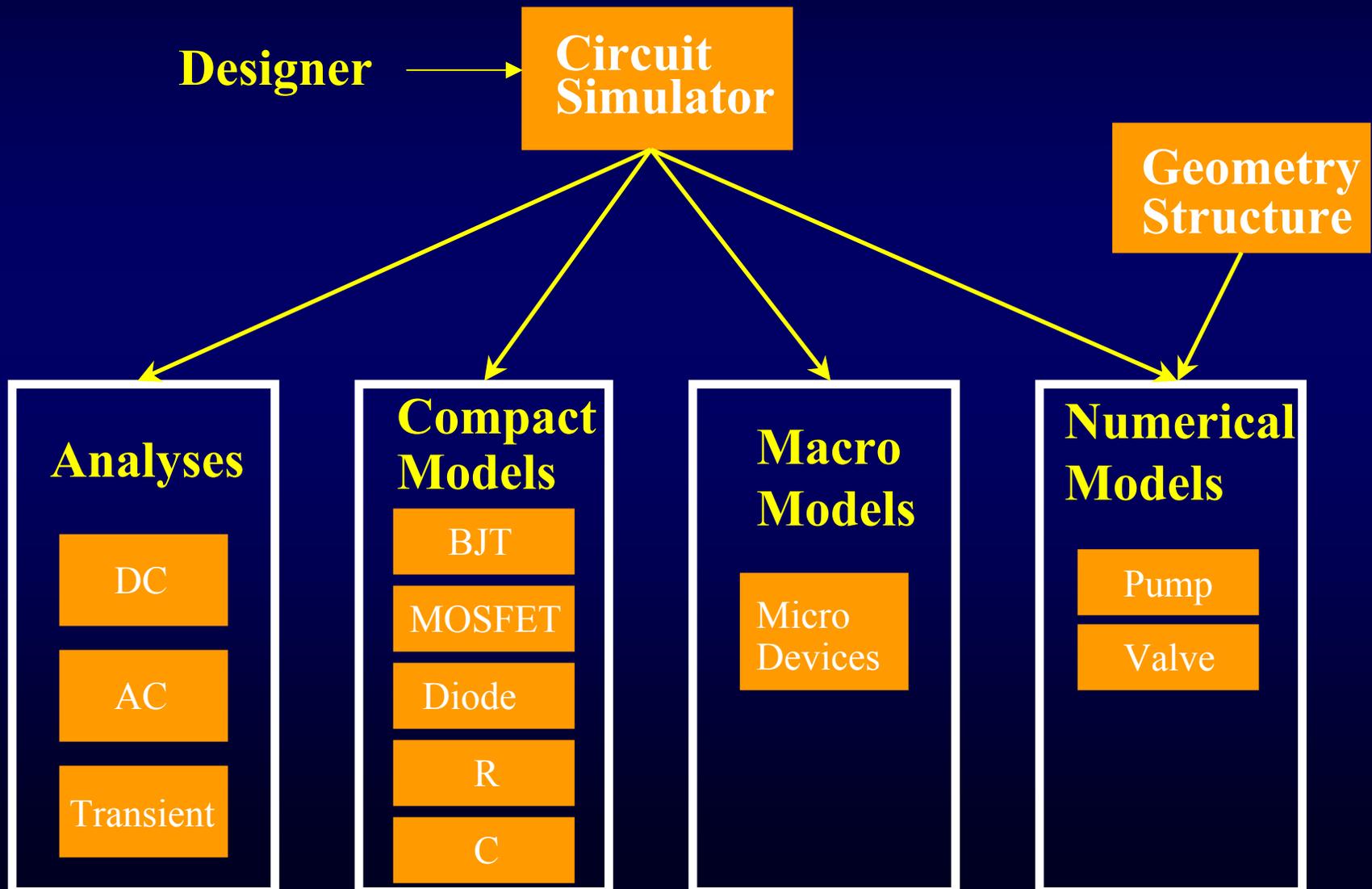
reach substrate

Comb structure



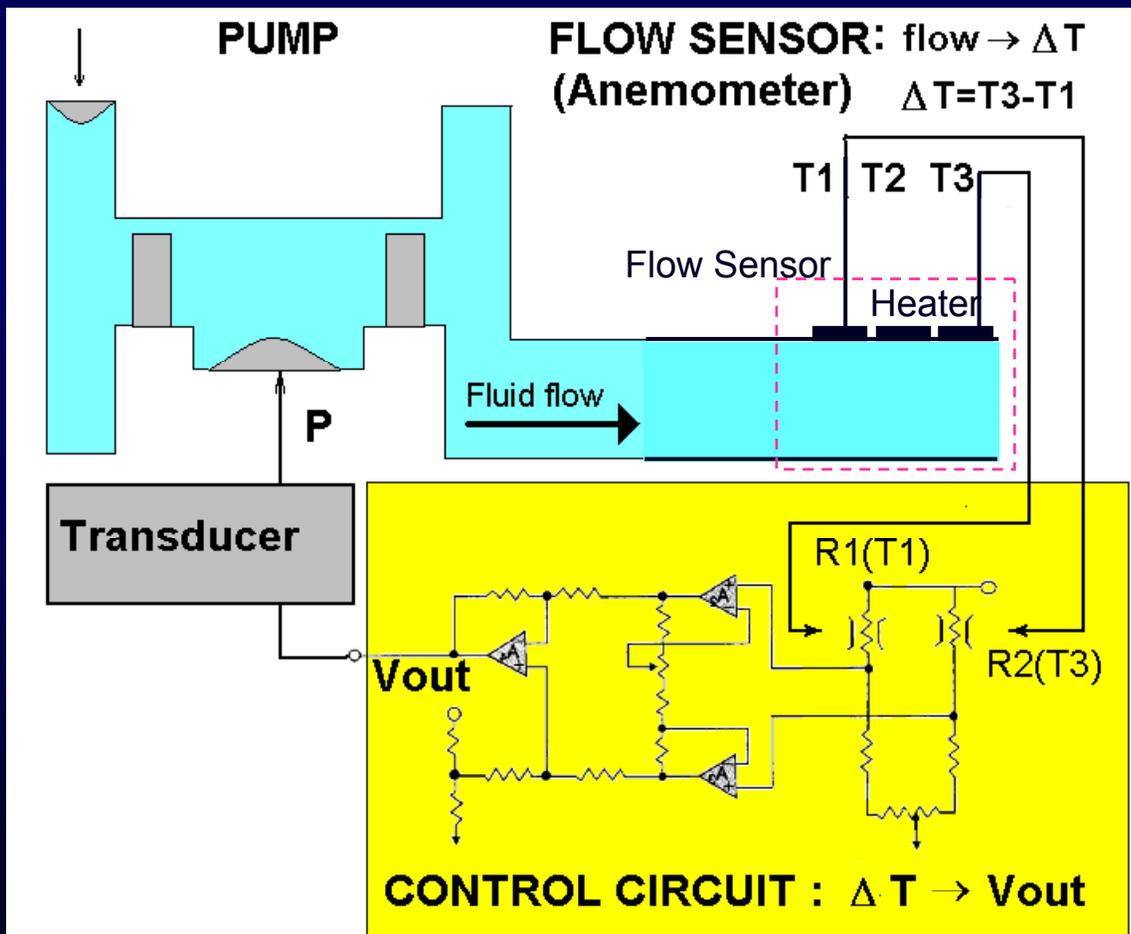
reach limit stops

# Coupled Circuit/Microdevice Simulator



# Micro Fluidic Simulation Example

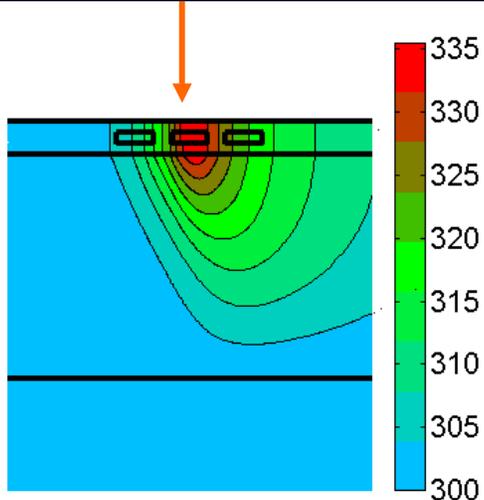
- Constant flow system



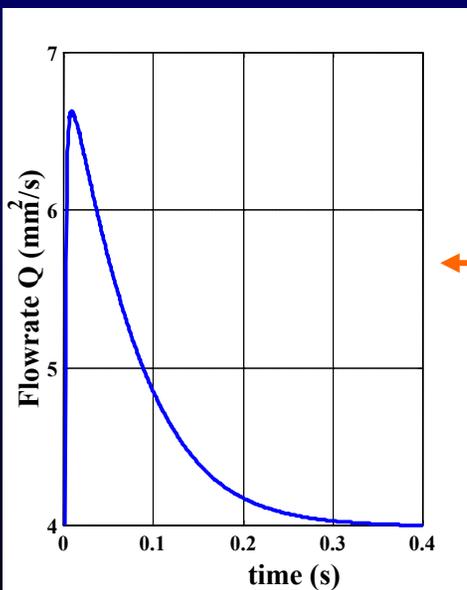
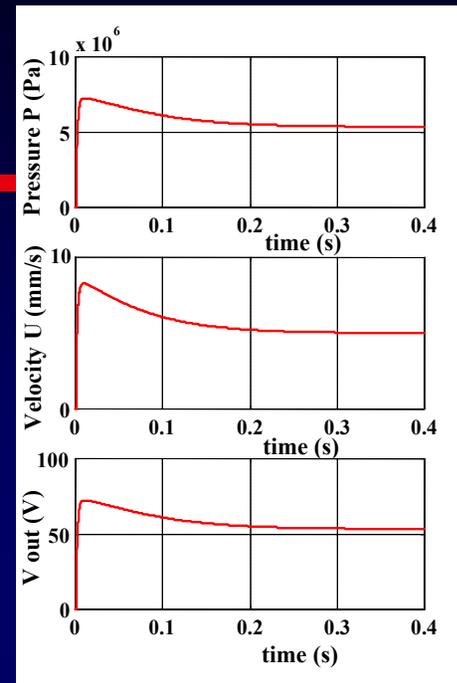
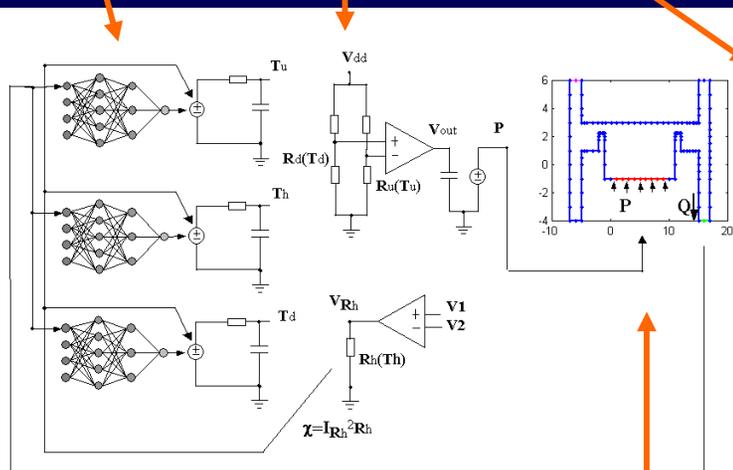


# Coupled System Simulation: 4 Physical Domains

Flow sensor: Flow to Temperature (thermal domain)

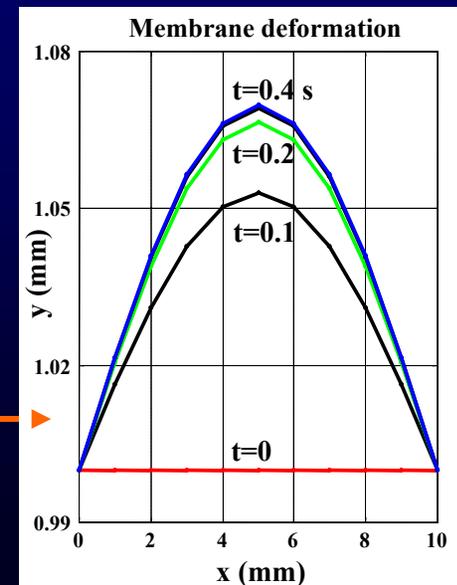


Circuit: Temperature to Voltage (electrical domain)



Micropump: Displacement to Flow (fluid domain)

Piezo-actuator: Voltage to Displacement (structure domain)



# Conclusions

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- **Coupled circuit/device simulations required for accurate simulation of circuits/systems**
- **Provides a direct link between technology changes and circuit performance**
- **Also useful for developing accurate compact models**
- **Need faster solution methods for PDEs**
- **Different coupling algorithms need to be developed for various problem domains**